

P-Channel 40 V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^a	Q _g (Typ.)			
- 40	0.010 at V _{GS} = - 10 V	- 16.1	33 nC			
- 40	0.014 at V _{GS} = - 4.5 V	- 13.3	33110			

FEATURES

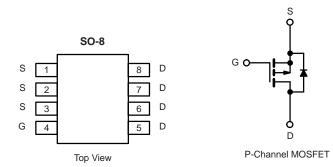
- Halogen-free According to IEC 61249-2-21 Definition
- 100 % R_g Tested
- 100 % UIS Tested
- Compliant to RoHS Directive 2002/95/EC



FREE



- Load Switch
- POL



Parameter Drain-Source Voltage Gate-Source Voltage		Symbol	Limit	Unit	
		V _{DS}	- 40 ± 20	V	
		V _{GS}			
	T _C = 25 °C		- 16.1		
Continuous Prais Current (T. 150 °C)	T _C = 70 °C		- 12.9		
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	I _D	- 10.2 ^{b, c}		
	T _A = 70 °C		- 8.2 ^{b, c}		
Pulsed Drain Current		I _{DM}	- 50	A	
Continous Source-Drain Diode Current	T _C = 25 °C		- 5.3		
Continous Source-Drain Diode Current	T _A = 25 °C	l _s	- 2.1 ^{b, c}		
Single Pulse Avalanche Current	1 0411	I _{AS}	- 28		
Single Pulse Avalanche Energy L = 0.1 mH		E _{AS}	39	mJ	
	T _C = 25 °C		6.3		
Maximum Power Dissipation	T _C = 70 °C	1 , [4	W	
	T _A = 25 °C	P _D	2.5 ^{b, c}	VV	
	T _A = 70 °C		1.6 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stq}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS							
Parameter	Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	37	50	°C/W		
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	16	20	10/00		

Notes:

- a. Based on T_C = 25 °C.
 b. Surface mounted on 1" x 1" FR4 board.
- d. Maximum under steady state conditions is 85 °C/W.



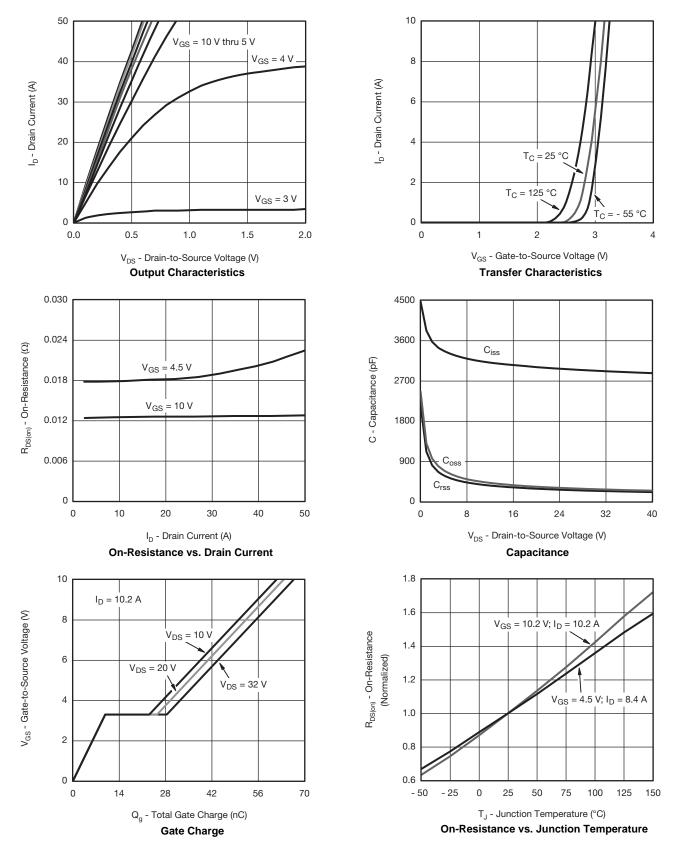
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V, } I_D = -250 \mu\text{A}$	- 40			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 250 A		- 36		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = - 250 μA		5			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = -250 \mu A$	- 1.2		- 2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zana Oata Valtana Busis Osumast	I _{DSS}	V _{DS} = - 40 V, V _{GS} = 0 V			- 1	μА	
Zero Gate Voltage Drain Current		V _{DS} = - 40 V, V _{GS} = 0 V, T _J = 55 °C			- 5		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \le -5 \text{ V}, V_{GS} = -10 \text{ V}$	- 25			Α	
Davis Course Co Ciata Davista and	В	V _{GS} = - 10 V, I _D = - 10.2 A		0.010			
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 8.4 A		0.014		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 10.2 A		37		S	
Dynamic ^b	-				•		
Input Capacitance	C _{iss}			3007		pF	
Output Capacitance	C _{oss}	$V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		335			
Reverse Transfer Capacitance	C _{rss}			291			
Total Octo Observe	0	$V_{DG} = -20 \text{ V}, V_{GG} = -10 \text{ V}, I_{D} = -10.2 \text{ A}$		64	95	nC	
Total Gate Charge	Q_g			33	50		
Gate-Source Charge	Q_{gs}	$V_{DS} = -20 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -10.2 \text{ A}$		9.8			
Gate-Drain Charge	Q _{gd}			15.7			
Gate Resistance	R _g	f = 1 MHz	0.4	2	4	Ω	
Turn-On Delay Time	t _{d(on)}			57	86		
Rise Time	t _r	V_{DD} = - 20 V, R_L = 2.4 Ω		50	75	ns	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 8.2 A, V_{GEN} = - 4.5 V, R_g = 1 Ω		40	60		
Fall Time	t _f			17	26		
Turn-On Delay Time	t _{d(on)}			13	20		
Rise Time	t _r	$V_{DD} = -20 \text{ V}, R_{L} = 2.4 \Omega$		11	20		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 8.2 A, V_{GEN} = - 10 V, R_g = 1 Ω		45	68		
Fall Time	t _f			9	18		
Drain-Source Body Diode Characteristi	cs				•		
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			- 5.3	Δ	
Pulse Diode Forward Current	I _{SM}				- 50	A	
Body Diode Voltage	V_{SD}	I _S = - 8.2 A, V _{GS} = 0 V		- 0.8	- 1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			36	54	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = - 8.2 A, dl/dt = 100 A/μs, T _J = 25 °C		41	62	nC	
Reverse Recovery Fall Time	t _a			20			
Reverse Recovery Rise Time	t _b			16		ns	

Notes:

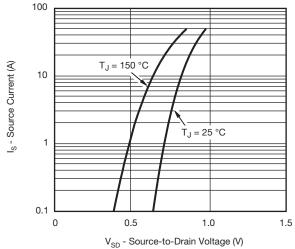
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

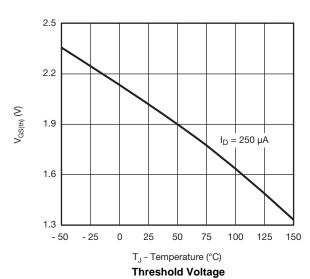






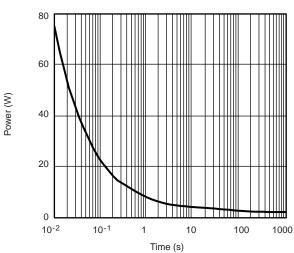




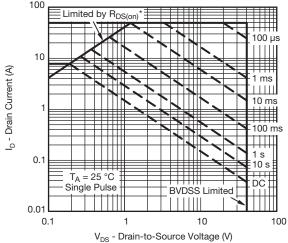


0.05
0.04
0.04
0.03
0.02
0.01 $T_{J} = 125 \, ^{\circ}\text{C}$ 0.01 V_{GS} - Gate-to-Source Voltage (V)

On-Resistance vs. Gate-to-Source Voltage



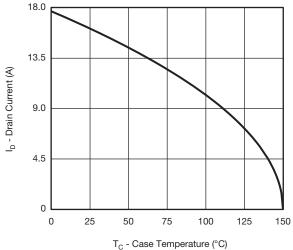
Single Pulse Power (Junction-to-Ambient)



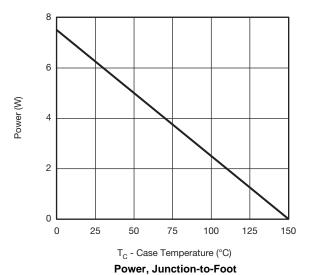
* V_{GS} > minimum V_{GS} at which R_{DS(on)} is specified

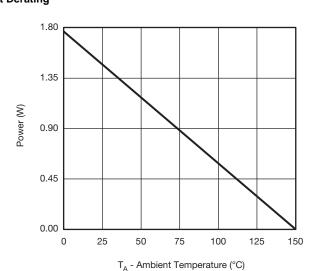
Safe Operating Area, Junction-to-Ambient





Current Derating*

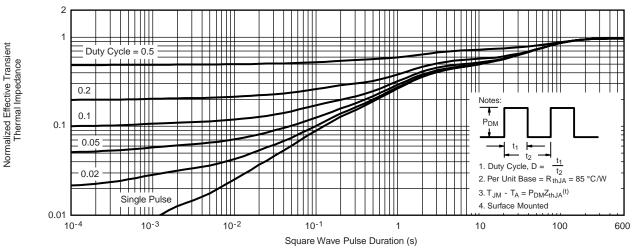




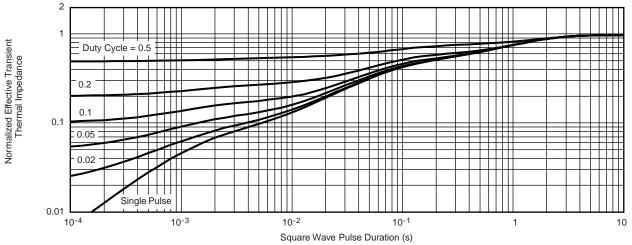
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





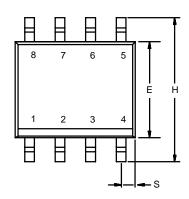
Normalized Thermal Transient Impedance, Junction-to-Ambient

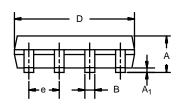


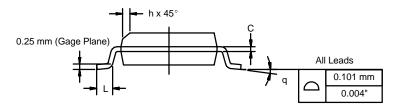
Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEADJEDEC Part Number: MS-012







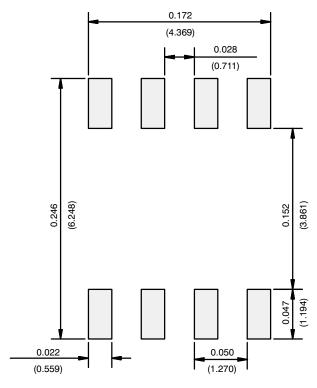
	MILLIM	IETERS	INCHES		
DIM	Min	Max	Min	Max	
А	1.35	1.75	0.053	0.069	
A ₁	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27	BSC	0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
ECN: C-06527-Rev. I, 11-Sep-06					

DWC: 5409

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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